National University of Singapore	CIBA Faculty of Sc	ience, Dept of Physic ,Centre of Ion	Beam Applications	Procedure No:	CIBA/SOP/Eq/013
Title: Operation	on of 20 deg beamline	Rev No: Issue Date:	0001		
				Page:	1 of 2
Prepared by:	Jeroen van Kan	Approved by:	Jeroen van Kan	Review Date: 01/11/2011	

## 1 Objective:

This Standard Operation Procedure states how to use 20 deg beam line for fabricating micro/nano structures on resists.

## 2 Responsibilities:

#### 2.1 Director / HOD / PI

The Director/HOD/PI has overall responsibility for ensuring a process is designed for the safe to fabricate micro/nano structures at 20 deg beam line.

## 2.2 Designated Person

There shall be a designated person to oversee the correct procedures of fabrication micro/nano structures at 20 deg beam line.

### 2.3 Staff/ Research personnel

- a. Users shall attend appropriate training on the safe use of 20 deg beam line.
- Users shall report any injuries, defects or breakdowns to their supervisor.

#### 3 Personal Protection Equipment

When handling samples during operation at 20 deg beam line requires special protection equipment including: rubber gloves.

#### 4 Procedures

# 4.1. Sample exchange in 20 deg chamber

- 4.1.1.Switch off the power supply for the CEM. Reduce RBS and or PIN bias gradually to 0V. Switch off the target stage.
- 4.1.2.Close the gate valve and the beam line valve to separate the sample chamber from the beam line and the accelerator and vent the chamber.
- 4.1.3. Take out the sample holder from the chamber.

#### 4.1.4. Wear gloves while handling samples and sample holder!

- 4.1.5. Transfer the sample holder in the chamber.
- 4.1.6. Close the venting valve and start roughing the chamber.
- 4.1.7. Wait until the chamber pressure is lower than 2\*10e-1 mbar, close the roughing valve and open the gate valve to the TMP.
- 4.1.8. Switch off the roughing-pump.

National University of Singapore	CIBA Faculty of Scient	Procedure No:	CIBA/SOP/Eq/013		
Title: Operation	on of 20 deg beamline	Rev No: Issue Date:	0001		
				Page:	2 of 2
Prepared by:	Jeroen van Kan	Approved by:	Jeroen van Kan	Review Date: 01/11/2011	

## 4.2. Running experiment

- 4.2.1. Bias the required detectors with the relevant voltages (as given by the manufacturer): RBS <20V, PIN =10V, CEM extra Bias <250V.
- 4.2.2. Make sure when the beam is transferred to the chamber, no detector is in line with the beam, or detector damage can occur.
- 4.2.3. When using CEM keep the current below 1 pA

# 4.3. Shutting down process

- 4.2.4.4.3.1. Put in Faraday Cup 2.
- 4.2.5.4.3.2. Turn off Blanking Power Suppler and terminate connections.
- 4.2.6.4.3.3. Follow 4.1.1 4.1.4 and take out your sample.
- 4.2.7.4.3.4. Follow 4.1.6 4.1.8 and pump down the chamber
- 4.2.8.4.3.5. Close the 20 deg beam line valve